MOSFET - Power, Single N-Channel, TOLL

40 V, 0.57 mΩ, 300 A

NVBLS0D5N04C

Features

- Low R_{DS(on)} to Minimize Conduction Losses
- Low Q_G and Capacitance to Minimize Driver Losses
- AEC-Q101 Qualified and PPAP Capable
- Small Footprint (TOLL) for Compact Design
- These Devices are Pb-Free, Halogen Free/BFR Free and are RoHS Compliant

MAXIMUM RATINGS (T_J = 25°C unless otherwise noted)

Parameter		Symbol	Value	Unit	
Drain-to-Source Voltage			V _{DSS}	40	V
Gate-to-Source Voltage	Э		V_{GS}	+20/–16	V
Continuous Drain Current R _{0JC} (Notes 1, 3)	Steady State	T _C = 25°C	I _D	300	Α
		T _C = 100°C		300	
Power Dissipation R ₀ JC (Note 1)		T _C = 25°C	P_{D}	198.4	W
		T _C = 100°C		97.4	
Continuous Drain		T _A = 25°C	I _D	65	Α
Current R _{θJA} (Notes 1, 2, 3)	Steady State	T _A = 100°C		46	
Power Dissipation		T _A = 25°C	P_{D}	4.3	W
R _{θJA} (Notes 1, 2)		T _A = 100°C		2.1	
Pulsed Drain Current	$T_A = 25^{\circ}C, t_p = 10 \mu s$		I _{DM}	4700	Α
Operating Junction and Storage Temperature Range		T _J , T _{stg}	-55 to +175	°C	
Source Current (Body Diode)		Is	170	Α	
Single Pulse Drain-to-Source Avalanche Energy (I _{L(pk)} = 55 A, L = 1 mH)		E _{AS}	1512	mJ	
Lead Temperature for Soldering Purposes (1/8" from case for 10 s)		TL	260	°C	

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

THERMAL RESISTANCE MAXIMUM RATINGS

Parameter	Symbol	Value	Unit
Junction-to-Case - Steady State	$R_{\theta JC}$	0.77	°C/W
Junction-to-Ambient - Steady State (Note 2)	$R_{\theta JA}$	35	

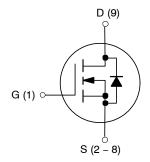
- The entire application environment impacts the thermal resistance values shown, they are not constants and are only valid for the particular conditions noted. Current is limited by bondwire configuration.
- 2. Surface-mounted on FR4 board using a 650 mm², 2 oz. Cu pad.
- Maximum current for pulses as long as 1 second is higher but is dependent on pulse duration and duty cycle.



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V _{(BR)DSS}	R _{DS(ON)} MAX	I _D MAX
40 V	0.57 m Ω @ 10 V	300 A



N-CHANNEL MOSFET



H-PSOF8L CASE 100CU

ORDERING INFORMATION

Device	Package	Shipping [†]			
NVBLS0D5N04CTXG	H-PSOF8L (Pb-Free)	2000 / Tape & Reel			

†For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specification Brochure, BRD8011/D.

Table 1. ELECTRICAL CHARACTERISTICS (T_J = 25°C unless otherwise noted)

Parameter	Symbol	Test Conditions		Min	Тур	Max	Units
OFF CHARACTERISTICS	•	•					
Drain-to-Source Breakdown Voltage	V _{(BR)DSS}	$I_D = 250 \mu\text{A}, V_{GS} = 0 \text{V}$		40			V
Drain-to-Source Breakdown Voltage Temperature Coefficient	V _{(BR)DSS} /T _J				21.3		mV/°C
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} = 40 V, V _{GS} = 0 V	T _J = 25°C			1	μΑ
			T _J = 175°C			1	mA
Gate-to-Source Leakage Current	I _{GSS}	V _{DS} = 0 V, V _{GS} = +20/–16 V				±100	nA
ON CHARACTERISTICS (Note 4)							
Gate Threshold Voltage	V _{GS(th)}	$V_{GS} = V_{DS}, I_{D}$	= 475 μΑ	2	2.8	4	V
Threshold Temperature Coefficient	V _{GS(th)} /T _J				-7.4		mV/°C
Drain-to-Source On Resistance	R _{DS(on)}	V _{GS} = 10 V, I _D = 50 A			0.5	0.57	mΩ
CHARGES, CAPACITANCES & GATE RE	SISTANCE			•			
Input Capacitance	C _{iss}	$V_{GS} = 0 \text{ V}, V_{DS} = 25 \text{ V}, f = 1 \text{ MHz}$			12600		pF
Output Capacitance	C _{oss}				6705		pF
Reverse Transfer Capacitance	C _{rss}				227		pF
Gate Resistance	Rg	V _{GS} = 0.5 V, f = 1 MHz			1.8		Ω
Total Gate Charge	Q _{G(tot)}	V _{GS} = 10 V, V _{DS} = 20 V, I _D = 50 A			185		nC
Threshold Gate Charge	Q _{G(th)}	V _{GS} = 0 to 2 V			22		nC
Gate-to-Source Gate Charge	Q _{gs}	V _{DD} = 32 V, I _D = 50 A			48		nC
Gate-to-Drain "Miller" Charge	Q _{gd}				38		nC
Plateau Voltage	V_{GP}				4.2		V
SWITCHING CHARACTERISTICS (Note 5)						
Turn-On Delay Time	t _{d(on)}	V_{GS} = 10 V, V_{DD} = 20 V, I_{D} = 50 A, R_{GEN} = 6 Ω			40		ns
Turn-On Rise Time	t _r	$I_D = 50 \text{ A}, H_G$	EN = 6 Ω		84		ns
Turn-Off Delay Time	t _{d(off)}				164		ns
Turn-Off Fall Time	t _f				81		ns
DRAIN-SOURCE DIODE CHARACTERIS	TICS	•			-	-	-
Source-to-Drain Diode Voltage	V_{SD}	I _{SD} = 50 A, V	_{GS} = 0 V		0.76	1.2	V
Reverse Recovery Time	t _{rr}	V_{GS} = 0 V, dI_S/d_t = 100 A/ μ s, I_S = 50 A			108		ns
Charge Time	ta				62		ns
Discharge Time	t _b				46		ns
Reverse Recovery Charge	Q _{rr}				288		nC

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

4. Pulse Test: pulse width $\leq 300~\mu s$, duty cycle $\leq 2\%$.

5. Switching characteristics are independent of operating junction temperatures

TYPICAL CHARACTERISTICS

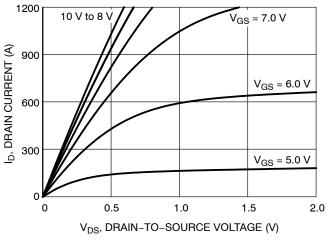
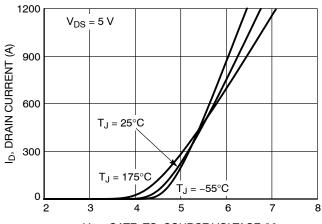


Figure 1. On-Region Characteristics



V_{GS}, GATE-TO-SOURCE VOLTAGE (V) Figure 2. Transfer Characteristics

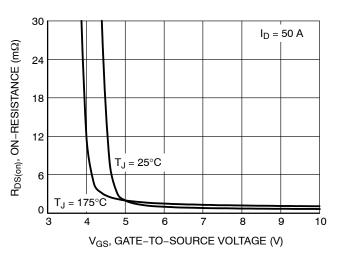


Figure 3. On-Resistance vs. Gate-to-Source Voltage

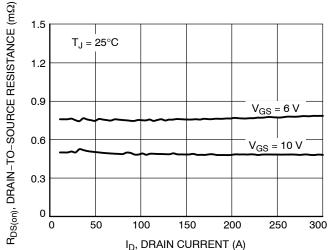


Figure 4. On-Resistance vs. Drain Current and Gate Voltage

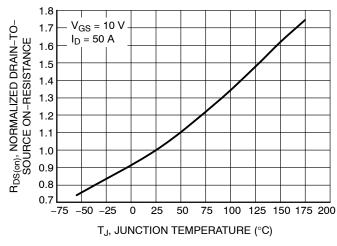


Figure 5. On–Resistance Variation with Temperature

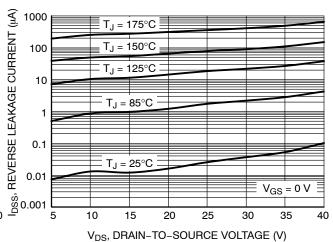


Figure 6. Drain-to-Source Leakage Current vs. Voltage

TYPICAL CHARACTERISTICS

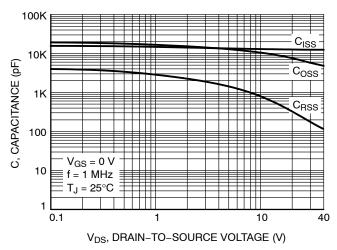


Figure 7. Capacitance Variation

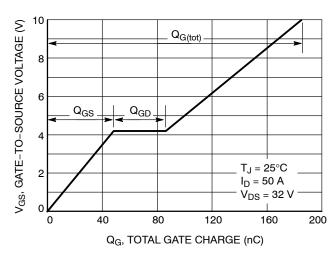


Figure 8. Gate-to-Source Voltage vs. Total Charge

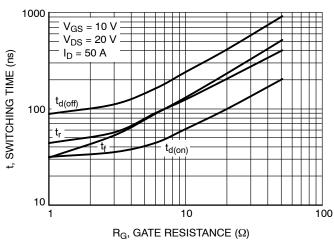


Figure 9. Resistive Switching Time Variation vs. Gate Resistance

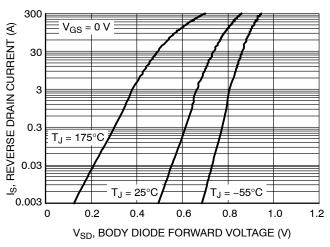


Figure 10. Diode Forward Voltage vs. Current

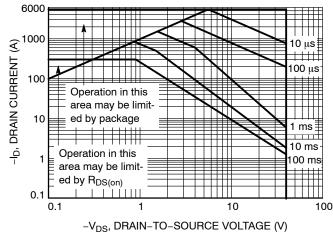


Figure 11. Forward Biased Safe Operating Area

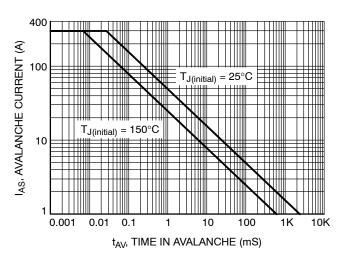


Figure 12. Maximum Drain Current vs. Time in Avalanche

TYPICAL CHARACTERISTICS

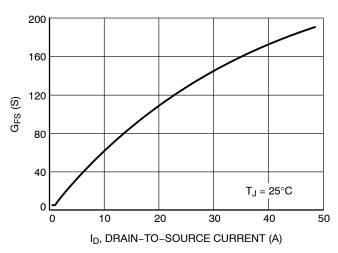


Figure 13. G_{FS} vs. I_D

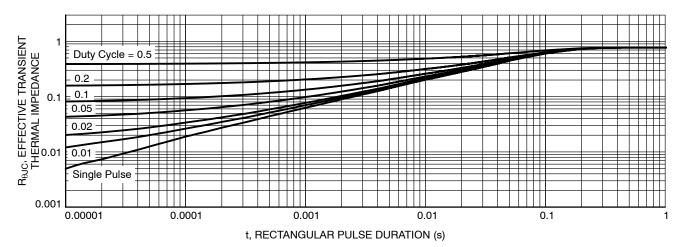
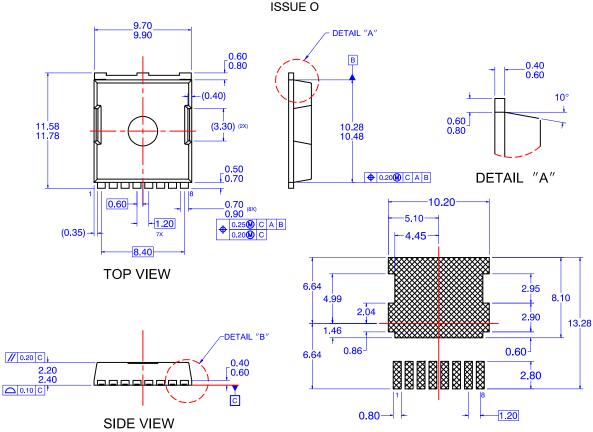


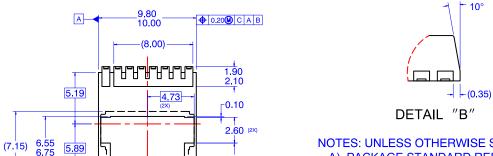
Figure 14. Transient Thermal Impedance

PACKAGE DIMENSIONS

H-PSOF8L 11.68x9.80 CASE 100CU



LAND PATTERN RECOMMENDATION



3.30 (2X)

0.65

NOTES: UNLESS OTHERWISE SPECIFIED

- A) PACKAGE STANDARD REFERENCE: JEDEC MO-299, ISSUE A, DATED NOVEMBER 2009.
- B) ALL DIMENSIONS ARE IN MILLIMETERS.
- C) DIMENSIONS DO NOT INCLUDE BURRS OR MOLD FLASH. MOLD FLASH OR BURRS DOES NOT EXCEED 0.10MM.
- D) DIMENSIONING AND TOLERANCING PER ASME Y14.5M-1994.

-(8.30)

3.75

-1,20

5.89

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